Se	earc	h N	otes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/708,276	LIU ET AL.	
Examiner	Art Unit	
Fsaw T Abraham	2133	

	SEARCHED			
		OHED		
Class	Subclass	Date	Examiner	
714	718, 719, 733	6/27/2006	EA	
365	201	6/27/2006	EΑ	
324	210	6/27/2006	EA	
360	26,47,53	6/27/2006	EA	
			•	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
,			

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East (USPT, JPO, EPO, DERWENT) (for text search) see search printout history.	6/27/2006	EA
Inventor's search was conducted for double patenting. No double patenting issue was found.	6/27/2006	EA
		, ,
		-